

# **IRF7470TRPBF-VB Datasheet** N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}\left(\Omega\right)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
40	0.0038 at V <sub>GS</sub> = 10 V	18	8 nC			
40	$0.0057 \text{ at V}_{GS} = 4.5 \text{ V}$	14.5	0110			

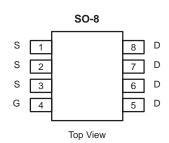
#### **FEATURES**

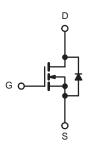
- Halogen-free According to IEC 61249-2-21
- Trench Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested

# COMPLIANT HALOGEN FREE

#### **APPLICATIONS**

- Notebook CPU Core
  - High-Side Switch





N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V <sub>DS</sub>	40	V	
Gate-Source Voltage		V <sub>GS</sub>	± 20	v	
	T <sub>C</sub> = 25 °C		18		
Continuous Drain Current (T <sub>.I</sub> = 150 °C)	T <sub>C</sub> = 70 °C		13.5		
Continuous Diain Current (1) = 150 °C)	T <sub>A</sub> = 25 °C	l <sub>D</sub>	12 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		9.6 <sup>b, c</sup>	^	
Pulsed Drain Current		I <sub>DM</sub>	50	Α	
Ocationary Oceans Brain Binds Oceans	T <sub>C</sub> = 25 °C	1-	4.5		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	ls —	2.2 <sup>b, c</sup>		
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	20		
Avalanche Energy	L = 0.1 IIII	E <sub>AS</sub>	20	mJ	
	T <sub>C</sub> = 25 °C		5		
Maximum Dawar Dissination	T <sub>C</sub> = 70 °C	P <sub>D</sub>	3.2	w	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C		2.5 <sup>b, c</sup>	VV	
	T <sub>A</sub> = 70 °C	1	1.6 <sup>b, c</sup>		
Operating Junction and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	$R_{thJA}$	38	50	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	$R_{thJF}$	20	25	J/ V V		

- a. Based on T<sub>C</sub> = 25 °C.
  b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V, } I_D = 250  \mu\text{A}$	40			V
V <sub>DS</sub> Temperature Coefficient	ΔV <sub>DS</sub> /T <sub>J</sub>	Vpe/Ti		34		m)//9
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- I <sub>D</sub> = 250 μA		- 4.7		mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1.0		3.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zara Cata Valtaria Brain Comment	I <sub>DSS</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V			1	μΑ
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A	0.0038			+
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 7 A		0.0057		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 10 A		30		S
Dynamic <sup>b</sup>						l
Input Capacitance	C <sub>iss</sub>			985		pF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz		205		
Reverse Transfer Capacitance	C <sub>rss</sub>	1		76		
Total Gate Charge		V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		18	27	nC
				8	12	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		2.4		
Gate-Drain Charge	Q <sub>gd</sub>	1		2.3		
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.3	1.3	2.6	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			14	25	
Rise Time	t <sub>r</sub>	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		12	24	- - ns -
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		19	35	
Fall Time	t <sub>f</sub>	1		9	18	
Turn-On Delay Time	t <sub>d(on)</sub>			8	16	
Rise Time	t <sub>r</sub>	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		10	20	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		16	30	
Fall Time	t <sub>f</sub>			9	18	
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			4.5	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				50	A
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 3 A		0.76	1.1	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			14	28	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	1 - 10 A dl/dt - 100 A/vo T - 05 °C		5	10	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		8		
Reverse Recovery Rise Time	t <sub>b</sub>			6		ns

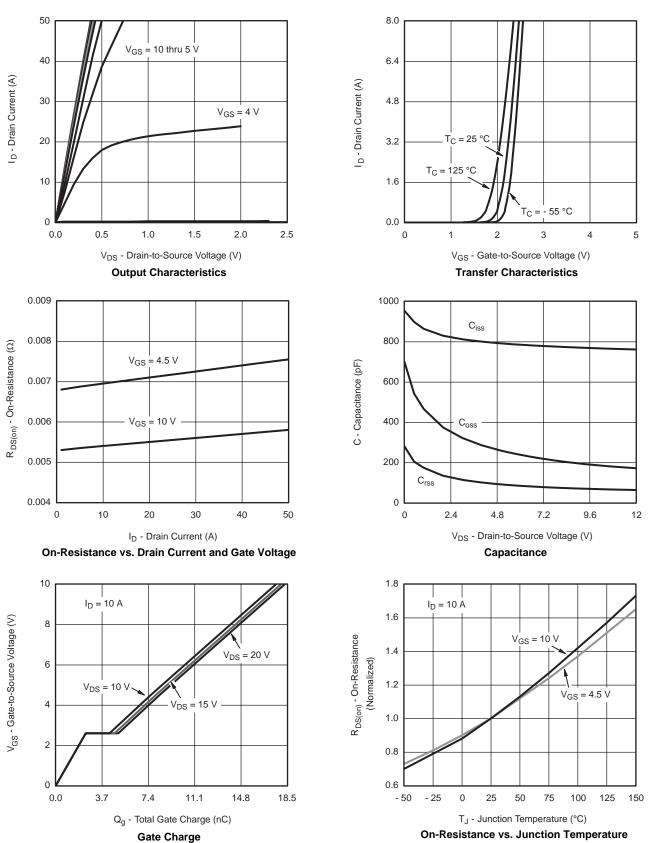
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,~duty~cycle \leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

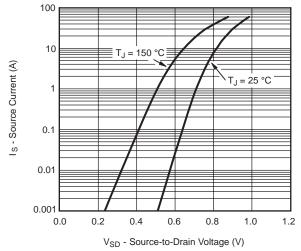


### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

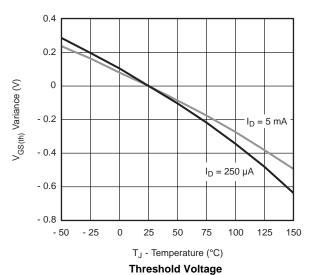


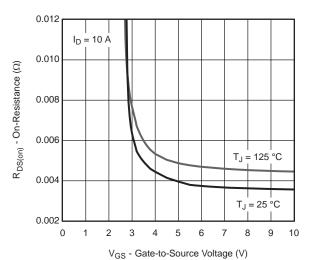


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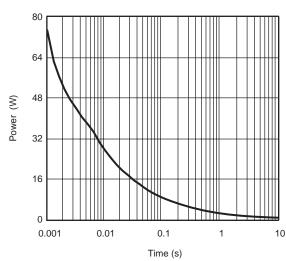


#### Source-Drain Diode Forward Voltage

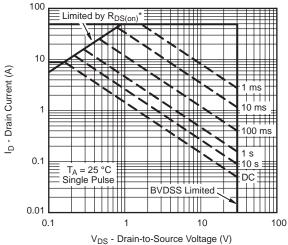




On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

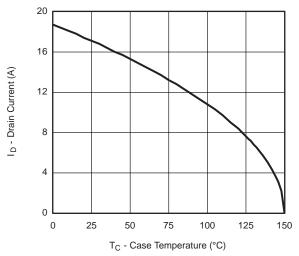


\* V<sub>GS</sub> > minimum V<sub>GS</sub> at which R<sub>DS(on)</sub> is specified

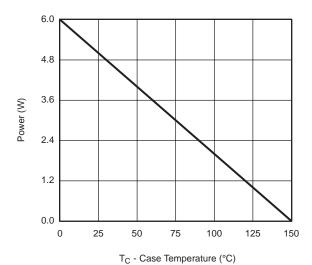
Safe Operating Area, Junction-to-Ambient

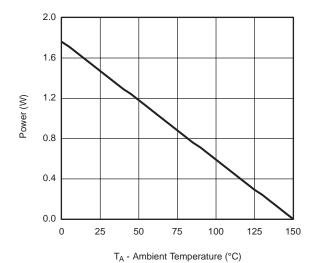


#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



#### Current Derating\*





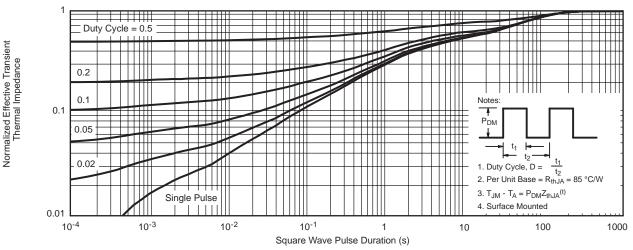
Power, Junction-to-Ambient

-Ambient Power Derating, Junction-to-Foot

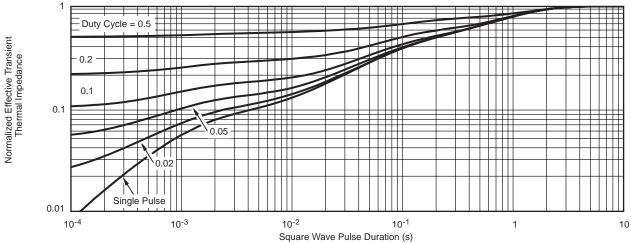
<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



#### TYPICAL CHARACTERISTICS 25 C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient

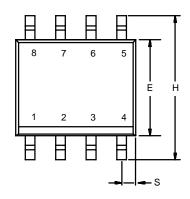


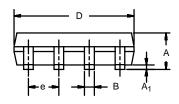
Normalized Thermal Transient Impedance, Junction-to-Foot

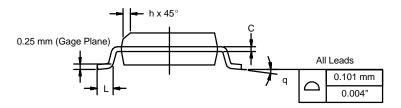
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**SOIC (NARROW): 8-LEAD**JEDEC Part Number: MS-012







	MILLIMETERS		INC	HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A <sub>1</sub>	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
Е	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev I 11-Sen-06					

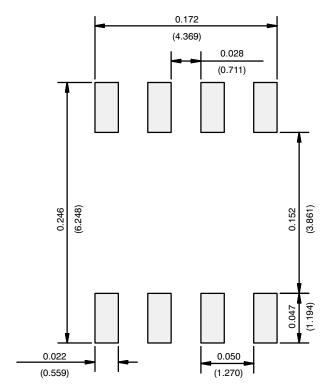
ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498

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#### **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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